## CHE323/384 Chemical Processes for Micro- and Nanofabrication Chris Mack, University of Texas at Austin

## Homework #4

- 1. Suppose we perform a solid solubility-limited predeposition from a doped glass source which introduces a total of Q impurities per square cm.
  - a. If this predeposition was performed for a total of *t* minutes, how long would it take (total time) to predeposit a total of 3Q impurities into a wafer if the predeposition temperature remained constant?
  - b. Derive a simple expression for the  $(Dt)_{drive-in}$  which would be required to drive the initial predeposition of Q impurities sufficiently deep so that the final surface concentration is equal to 1% of the solid solubility concentration. This can be expressed in terms of  $(Dt)_{predep}$  and the solid solubility concentration  $C_s$ .
- 2. A diffused region is formed by an ultra-shallow implant followed by a drive-in. The final profile is Gaussian.
  - a. Derive an expression for the junction depth  $(x_j)$  given a background dopant concentration (of the opposite type) of  $C_B$ .
  - b. Derive a simple expression for the sensitivity of  $x_j$  to the implant dose Q. Is  $x_j$  more sensitive to Q at high or low doses?
- 3. Campbell textbook, Chapter 3, problem 7.